Lab Code: 200707-0

AS/NZS CISPR 22: 2009 Class B

TEST REPORT

For

YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.

4th-5th Floor, South Building, NO. 63 WangHai Road, 2nd Software Park, Xiamen, China

Model: W52P, W52H, W52Duo

Report Type:	**Product Name:**
Original Report	IP DECT Phone

Test Engineer:	Andrew Shu
Report Number:	RSZ120919005-09
Report Date:	2012-12-17
Reviewed By:	Dick Zhang EMC Leader
Test Laboratory:	Bay Area Compliance Laboratories Corp. (Shenzhen) 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China Tel: +86-755-33320018 Fax: +86-755-33320008 www.baclcorp.com.cn

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GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

The *YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.'s* product, model number: *W52P* or the "EUT" in this report was a *IP DECT Phone*, which was measured approximately: 15.5 cm (L) x 11.0 cm (W) x 4.5 cm (H) for base, 14.5 cm (L) x 5.0 cm (W) x 2.5 cm (H) for handset, rated input: DC 5V for base and DC 5 V for handset, the highest operating frequency of EUT is 207 MHz.

Adapter information:
Model: OH-1048A0500600U2-SAA
Input: AC 100-240V, 50/60 Hz, 250 mA
Output: DC 5V, 600mA

Note: the series product, model W52P, W52H and W52Duo are electrically identical, the differences among them please refer to the attached declaration letter, which was stated and guarantied by the applicant. The model W52P was selected to test.

**All measurement and test data in this report was gathered from production sample serial number: 1209091 (Assigned by BACL, Shenzhen). The EUT supplied by the applicant was received on 2012-09-19.*

Objective

This test report is prepared on behalf of *YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.* in accordance with AS/NZS CISPR 22: 2009 Class B rules.

The objective of the manufacturer is to determine compliance with AS/NZS CISPR 22: 2009 Class B.

Related Submittal(s)/Grant(s)

No related submittal(s).

Test Methodology

All measurements contained in this report were conducted with CISPR 16-1-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P1-1: radio disturbance and immunity measuring apparatus measuring apparatus. CISPR 16-1-4:2010, Specification for radio disturbance and immunity measuring apparatus and methods-Part 1-4: Radio disturbance and immunity measuring apparatus -Ancillary equipment -Radiated disturbances. CISPR 16-2-1: 2010, specification for radio disturbance and immunity measuring apparatus and methods P2-1: methods of measurement of disturbance and immunity conducted disturbance measurements. CISPR 16-2-3: 2010, specification for radio disturbance and immunity measuring apparatus and methods P2-3 methods of measurement of disturbances and immunity radiated disturbance measurements. CISPR 16-4-2:2011, Specification for radio disturbance and immunity measuring apparatus and methods-Part 4-2: Uncertainties, statistics and limit modeling-Uncertainty in EMC measurements.

All radiated and conducted emissions measurement was performed at Bay Area Compliance Laboratories Corp. (Shenzhen). The radiated testing was performed at an antenna-to-EUT distance of 3 Meters.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on December 06, 2010. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2009.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

Additionally, Bay Area Compliance Laboratories Corp. (Shenzhen) is an ISO/IEC 17025 accredited laboratory, and is accredited by National Voluntary Laboratory Accredited Program (Lab Code 200707-0).

The current scope of accreditations can be found at http://ts.nist.gov/Standards/scopes/2007070.htm.

SYSTEM TEST CONFIGURATION

Justification

The system was configured for testing in a manufacturer testing fashion.

EUT Exercise Software

No exercise software was used.

Special Accessories

No special accessories

Equipment Modifications

No modification was made to the EUT tested.

Support Equipment List and Details

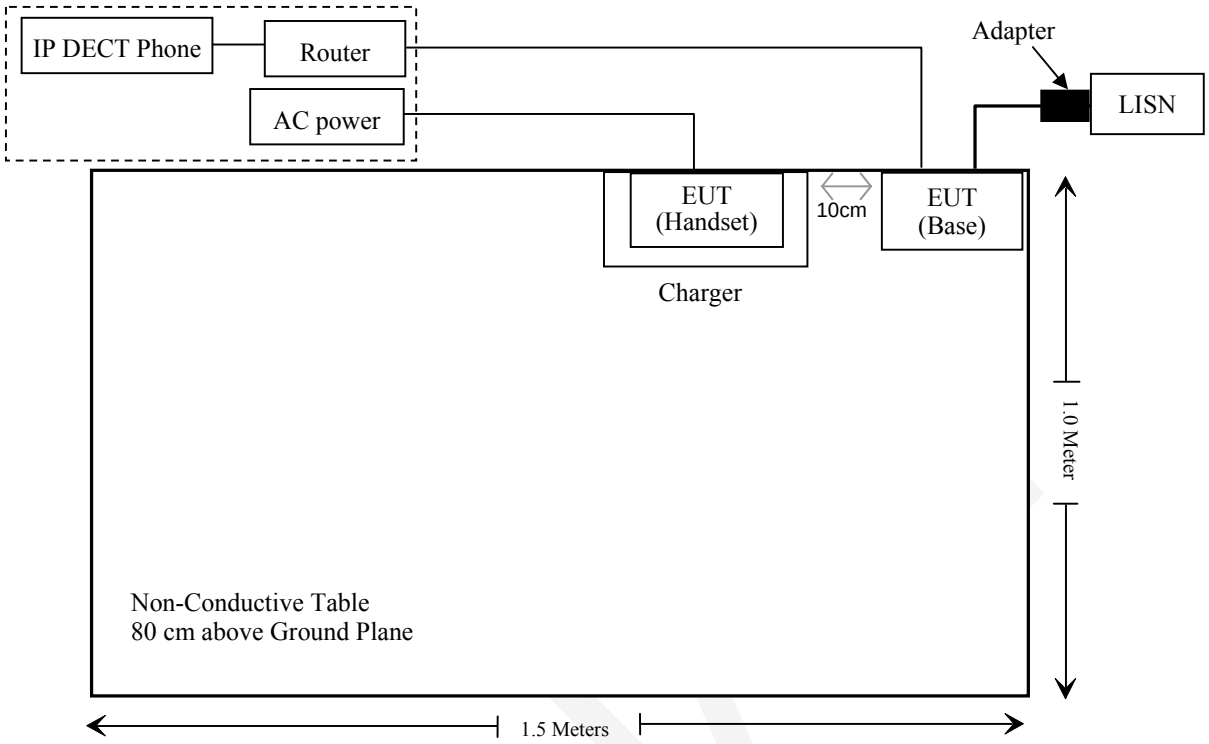
Manufacturer	Description	Model	Serial Number
NETGEAR	PoE Adapter	DSA-0421s-501	N/A
NETGEAR	PoE Switch	FS108P	N/A
Yealink	IP DECT Phone	W52P	N/A
N/A	Router	N/A	N/A

External I/O Cable

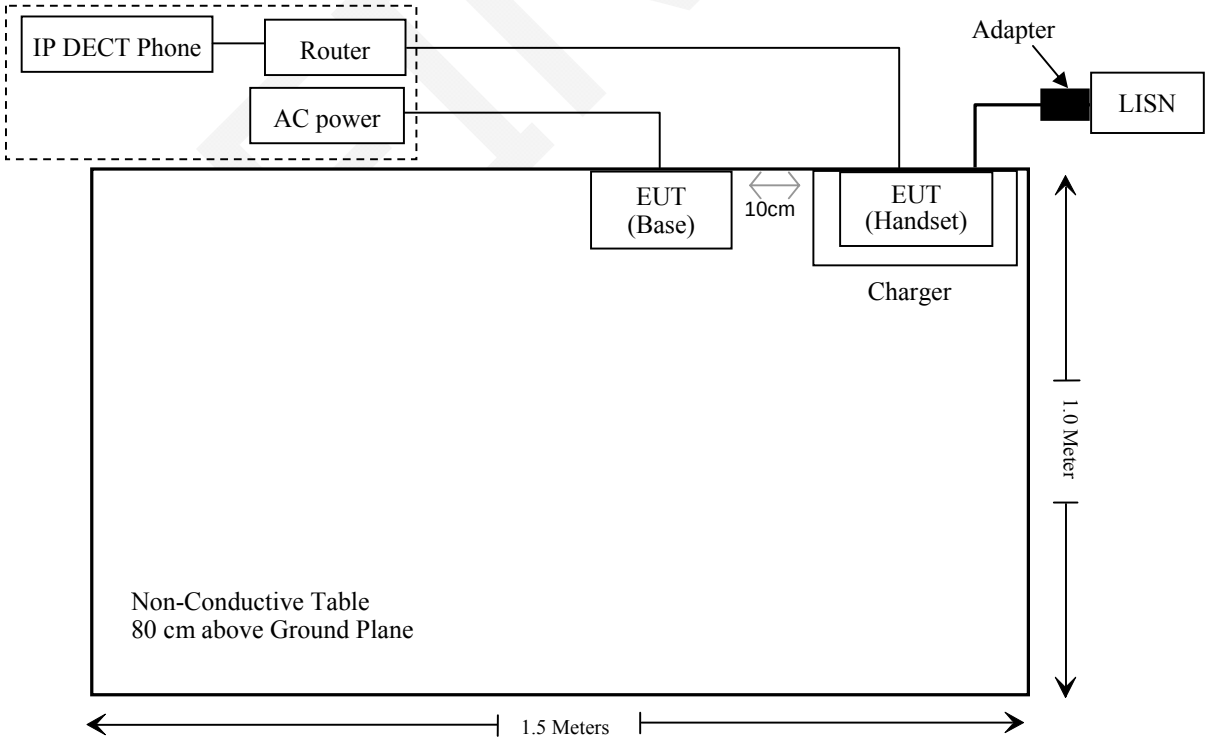
Cable Description	Length (m)	From/Port	To
Unshielded Undetachable DC Cable	1.5	Adapter	EUT BS or HS
Unshielded Undetachable DC Cable	1.5	Adapter	EUT HS or BS
Unshielded Detachable RJ45 Cable	3.0	Router	IP DECT Phone
Unshielded Detachable RJ45 Cable	3.0	Router	ISN
Unshielded Detachable RJ45 Cable	1.0	ISN	IP DECT Phone
Unshielded Detachable RJ45 Cable	3.0	Router	POE Switch
Unshielded Detachable RJ45 Cable	1.0	POE Switch	EUT BS
Unshielded Undetachable DC Cable	1.0	POE Switch	Adapter

Block Diagram of Test Setup

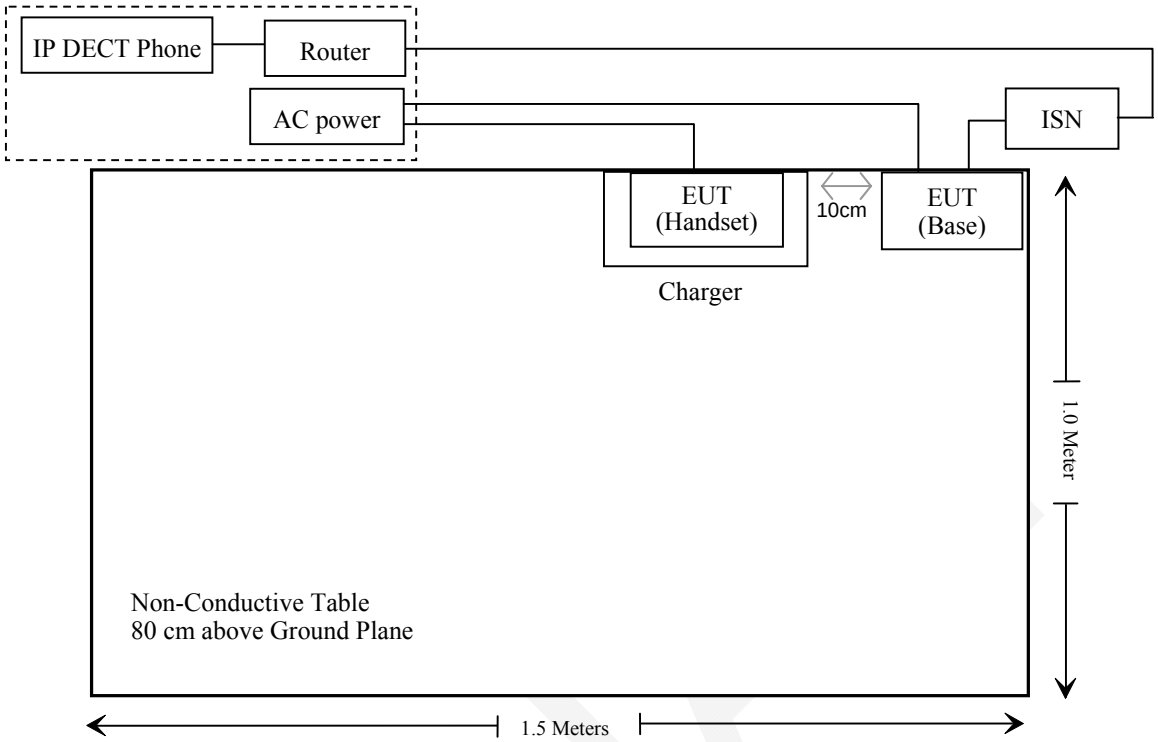
Powered by adapter (base)



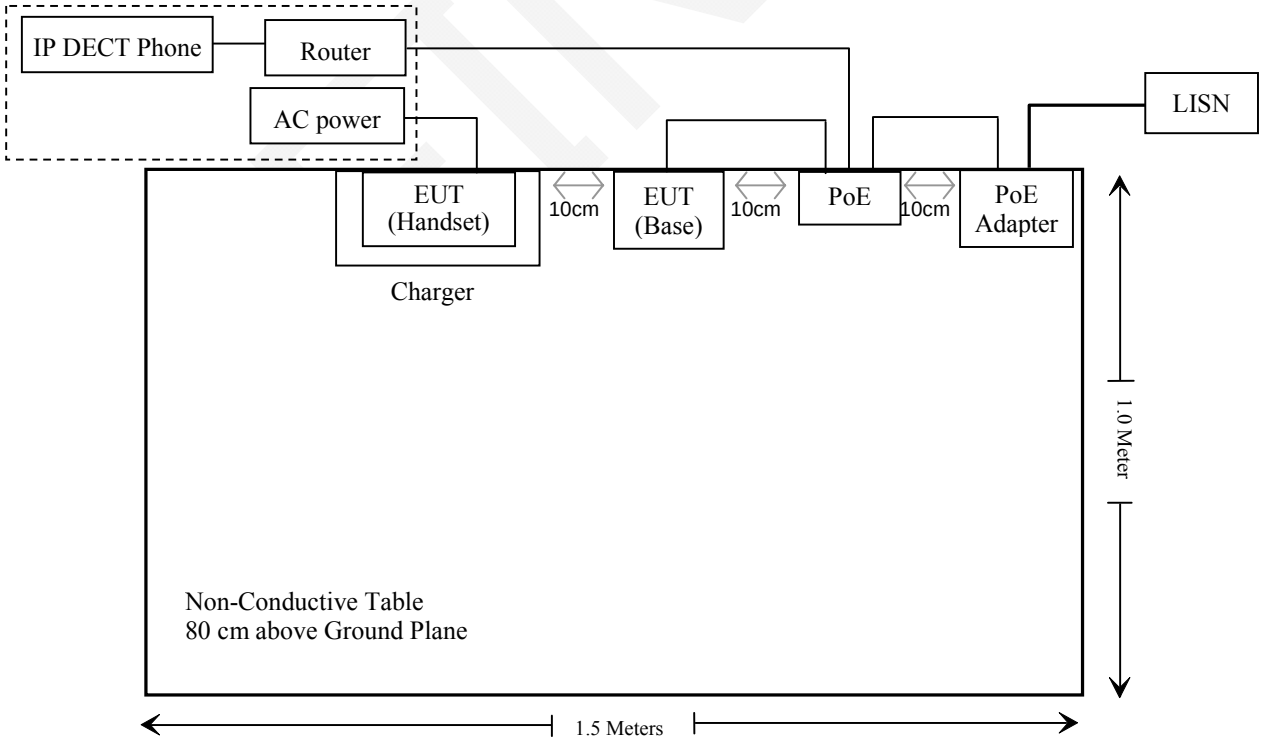
Powered by adapter (Handset)



Powered by adapter (RJ45 Port)



Powered by PoE



SUMMARY OF TEST REPORT

AS/NZS CISPR 22:2009

RULE	DESCRIPTION	RESULTS
§ 5.1	Conducted Disturbance at Mains Terminals	Compliance
§ 5.2	Conducted Disturbance at Telecommunication ports	Compliance
§ 6	Radiated Disturbance	Compliance

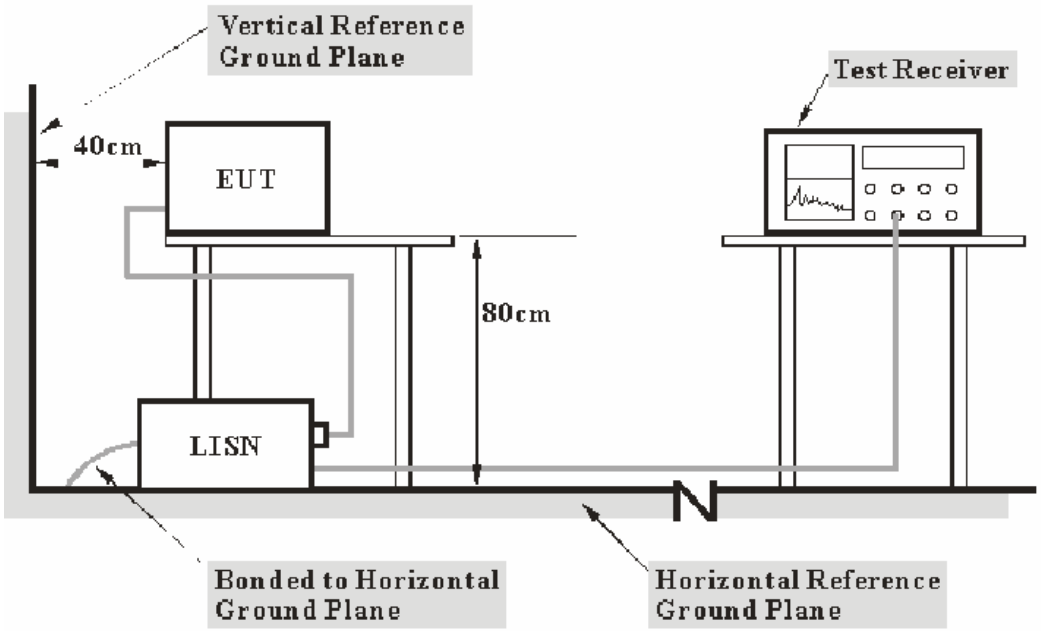
AS/NZS CISPR 22: 2009 §5.1 & 5.2 - CONDUCTED DISTURBANCE

Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, and LISN.

Based on CISPR 16-4-2, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is 2.4 dB.(k=2, 95% level of confidence), and the uncertainty will not be taken into consideration for all the test data recorded in the report.

Test System Setup



Note: 1. Support units were connected to second LISN.
2. Both of LISNs (AMN) 80 cm from EUT and at the least 80 cm from other units and other metal planes support units.

The measurement procedure is in according with CISPR 16-2-1:2010. The related limit was specified in the AS/NZS CISPR 22: 2009 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 240 VAC/50 Hz power source.

EMI Test Receiver Setup

The test receiver was set to investigate the spectrum from 150 kHz to 30 MHz.

During the conducted emission test, the EMI test receiver was set with the following configurations:

Frequency Range	IF B/W
150 kHz – 30 MHz	9 kHz

Test Procedure

During the conducted emission test, the adapter was connected to the LISN.

Maximizing procedure was performed on the six (6) highest emissions to ensure EUT compliance using all installation combination.

All data was recorded in the Quasi-peak and average detection mode.

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Rohde & Schwarz	EMI Test Receiver	ESCS30	100176	2011-11-24	2012-11-23
Rohde & Schwarz	L.I.S.N.	ESH2-Z5	892107/021	2012-08-22	2013-08-21
SCHWARZBECK	8 Wire ISN	NTFM 8158	8158-0011	2011-11-17	2012-11-16
Com-Power	L.I.S.N.	LI-200	12005	N/A	N/A
Rohde & Schwarz	Attenuator	ESH3Z2	DE25985	2012-07-08	2013-07-07
BACL	CE Test software	BACL-CE	V1.0	-	-

*** Statement of Traceability:** Bay Area Compliance Laboratory Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to National Institute of Metrology (NIM)

Corrected Factor & Margin Calculation

The Corrected factor is calculated by adding LISN/ISN VDF (Voltage Division Factor), Cable Loss and Pulse Limiter Attenuation. The basic equation is as follows:

Correction Factor = LISN VDF + Cable Loss + Pulse Limiter Attenuation

The "**Margin**" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7dB means the emission is 7 dB below the limit. The equation for margin calculation is as follows:

Margin = Limit – Corrected Amplitude

Test Results Summary

According to the recorded data in following table, the EUT complied with the AS/NZS CISPR 22: 2009 Class B, with the worst margin reading of:

0.47 dB at **23.130 MHz** in the **RJ45** conducted mode

Refer to CISPR16-4-2:2011 and CISPR 16-4-1 IEC:2009, the measured level is in compliance with the limit if

$$L_m + U_{(Lm)} \leq L_{lim} + U_{cispr}$$
$$\text{or } U_{(Lm)} \leq Margin + U_{cispr}$$

The measurement result of EUT is below the limit level by a margin 0.47 dB and
$U_{(Lm)}$(2.4dB)≤*Margin*(0.47dB) +U_{cispr}(3.4dB),
so the EUT complies with the limit of the AS/NZS CISPR 22: 2009 Class B.

Test Data

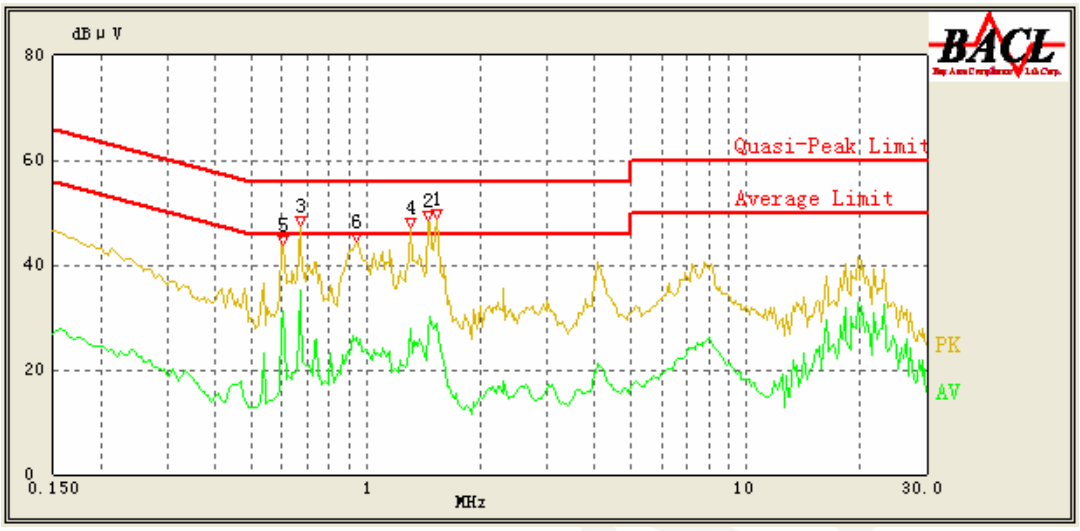
Environmental Conditions

Temperature:	25 ℃
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2012-09-22.

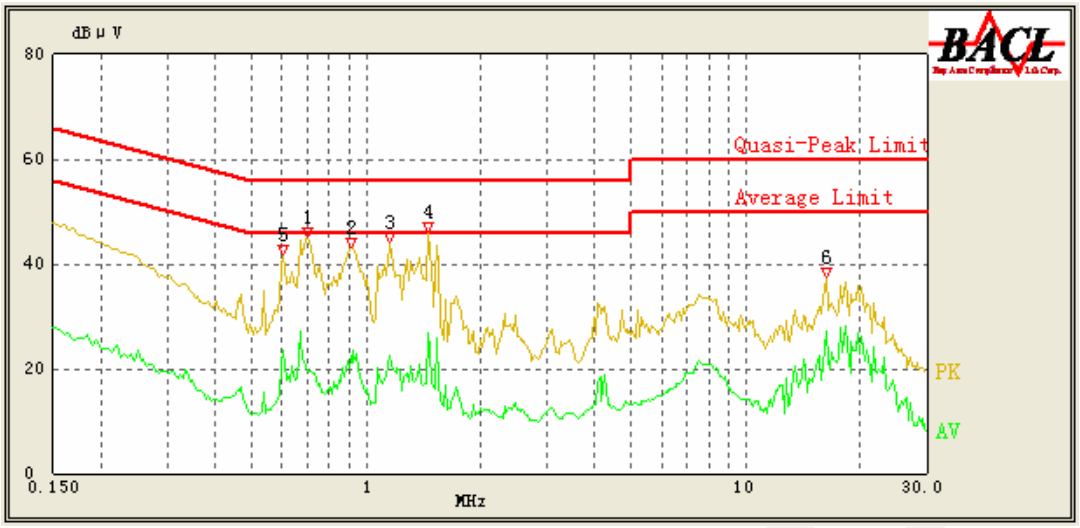
Test Mode: Talking (base-powered by adapter)

AC 240V/50 Hz, Line



Frequency (MHz)	Corrected Amplitude (dBµV)	Correction Factor (dB)	Limit (dBµV)	Margin (dB)	Detector (PK/Ave./QP)
0.670	45.25	10.22	56.00	10.75	QP
0.670	35.16	10.22	46.00	10.84	Ave.
1.535	43.07	10.19	56.00	12.93	QP
1.460	41.39	10.18	56.00	14.61	QP
0.605	31.22	10.23	46.00	14.78	Ave.
0.605	40.65	10.23	56.00	15.35	QP
1.305	40.35	10.18	56.00	15.65	QP
1.535	28.88	10.19	46.00	17.12	Ave.
1.305	27.97	10.18	46.00	18.03	Ave.
1.460	27.32	10.18	46.00	18.68	Ave.
0.945	26.18	10.18	46.00	19.82	Ave.
0.945	33.50	10.18	56.00	22.50	QP

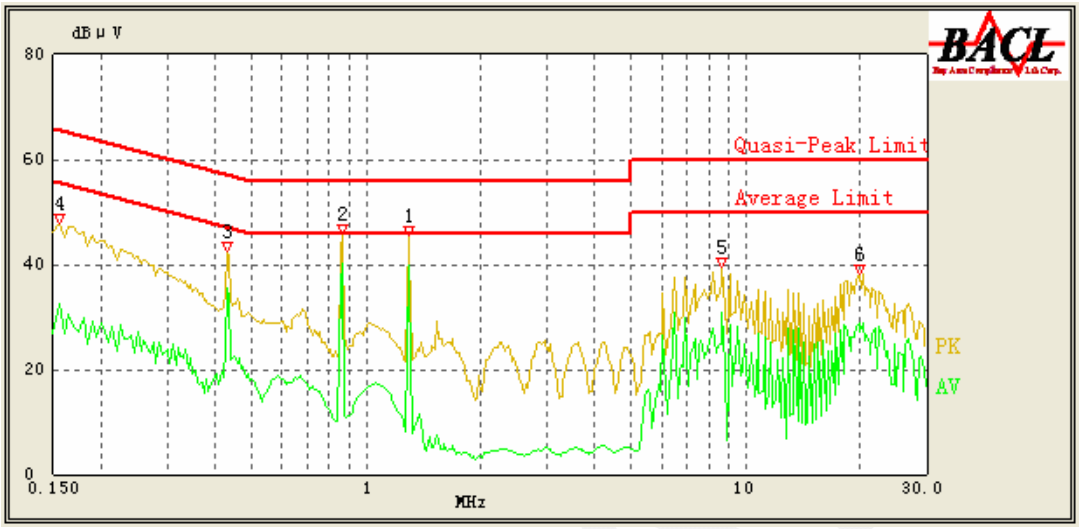
AC 240V/50 Hz, Neutral:



Frequency (MHz)	Corrected Amplitude (dBµV)	Correction Factor (dB)	Limit (dBµV)	Margin (dB)	Detector (PK/Ave./QP)
1.460	40.67	10.18	56.00	15.33	QP
0.605	38.43	10.23	56.00	17.57	QP
1.460	26.94	10.18	46.00	19.06	Ave.
1.155	36.80	10.17	56.00	19.20	QP
0.915	23.63	10.18	46.00	22.37	Ave.
0.605	23.40	10.23	46.00	22.60	Ave.
16.230	27.08	11.57	50.00	22.92	Ave.
1.155	22.39	10.17	46.00	23.61	Ave.
0.700	19.37	10.21	46.00	26.63	Ave.
0.700	27.36	10.21	56.00	28.64	QP
0.915	26.70	10.18	56.00	29.30	QP
16.230	29.91	11.57	60.00	30.09	QP

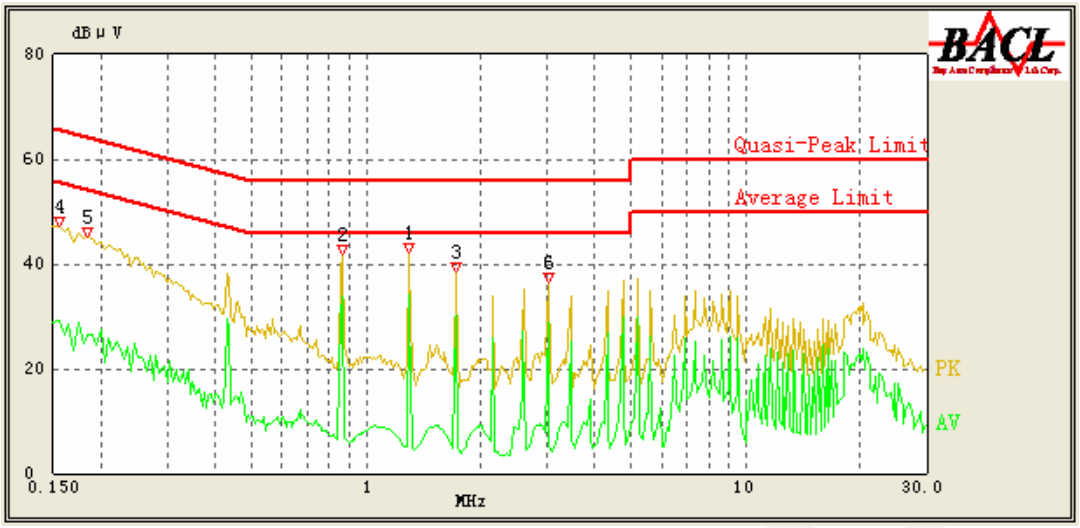
Test Mode: Talking (handset-powered by adapter)

AC 240V/50 Hz, Line



Frequency (MHz)	Corrected Amplitude (dBµV)	Correction Factor (dB)	Limit (dBµV)	Margin (dB)	Detector (PK/Ave./QP)
0.865	40.22	10.19	46.00	5.78	Ave.
1.295	39.90	10.18	46.00	6.10	Ave.
1.295	44.31	10.18	56.00	11.69	QP
0.865	44.09	10.19	56.00	11.91	QP
0.430	35.51	10.25	48.00	12.49	Ave.
0.430	40.23	10.25	58.00	17.77	QP
8.640	30.71	10.44	50.00	19.29	Ave.
0.155	46.20	10.24	65.86	19.66	QP
19.870	28.98	12.54	50.00	21.02	Ave.
0.155	32.54	10.24	55.86	23.32	Ave.
8.640	35.24	10.44	60.00	24.76	QP
19.870	34.24	12.54	60.00	25.76	QP

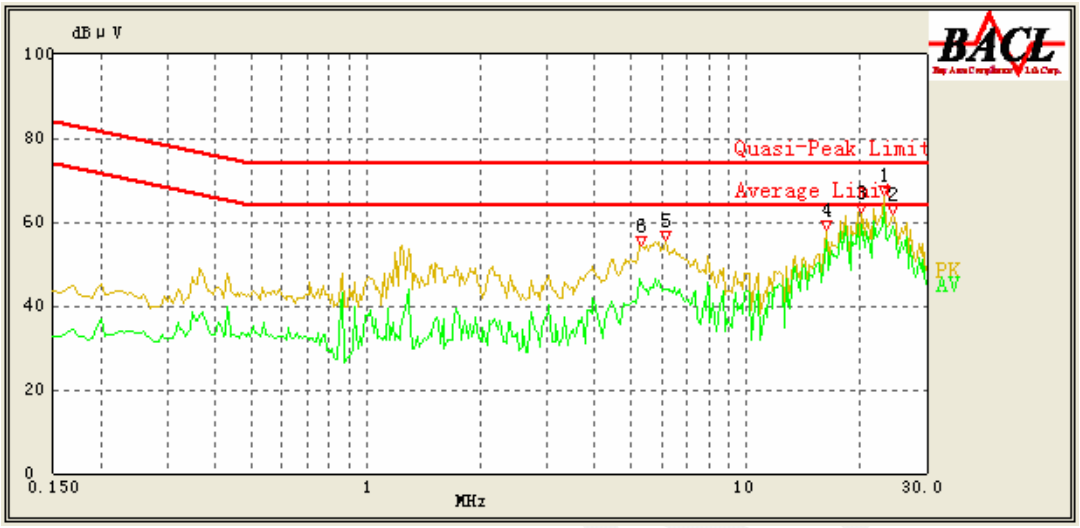
AC 240V/50 Hz, Neutral:



Frequency (MHz)	Corrected Amplitude (dBµV)	Correction Factor (dB)	Limit (dBµV)	Margin (dB)	Detector (PK/Ave./QP)
1.295	34.18	10.18	46.00	11.82	Ave.
0.865	33.79	10.19	46.00	12.21	Ave.
1.730	30.22	10.19	46.00	15.78	Ave.
0.865	39.25	10.19	56.00	16.75	QP
1.295	39.23	10.18	56.00	16.77	QP
3.025	28.84	10.23	46.00	17.16	Ave.
0.155	45.09	10.24	65.86	20.77	QP
1.730	35.02	10.19	56.00	20.98	QP
0.185	42.24	10.24	65.00	22.76	QP
3.025	32.59	10.23	56.00	23.41	QP
0.155	29.15	10.24	55.86	26.71	Ave.
0.185	26.41	10.24	55.00	28.59	Ave.

Test Mode: Talking (RJ45 Port)

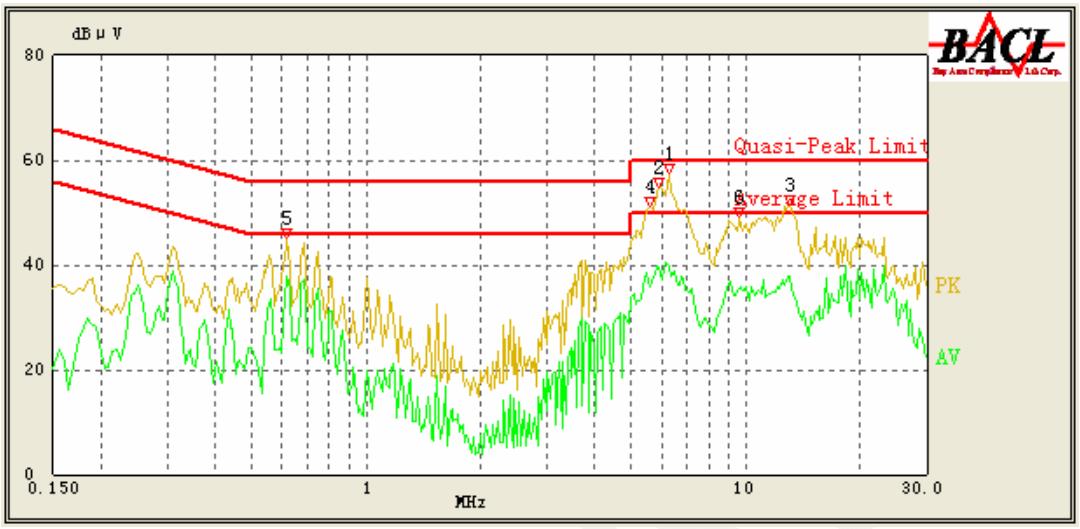
AC 240V/50 Hz, RJ 45



Frequency (MHz)	Corrected Amplitude (dBµV)	Correction Factor (dB)	Limit (dBµV)	Margin (dB)	Detector (PK/Ave./QP)
23.130	63.53	22.01	64.00	0.47*	Ave.
20.260	59.49	22.18	64.00	4.51	Ave.
24.350	58.93	21.94	64.00	5.07	Ave.
16.230	55.80	21.07	64.00	8.20	Ave.
23.130	65.06	22.01	74.00	8.94	QP
20.260	60.96	22.18	74.00	13.04	QP
24.350	60.73	21.94	74.00	13.27	QP
16.230	56.72	21.07	74.00	17.28	QP
5.300	45.55	19.51	64.00	18.45	Ave.
6.150	43.97	19.55	64.00	20.03	Ave.
5.300	50.77	19.51	74.00	23.23	QP
6.150	49.74	19.55	74.00	24.26	QP

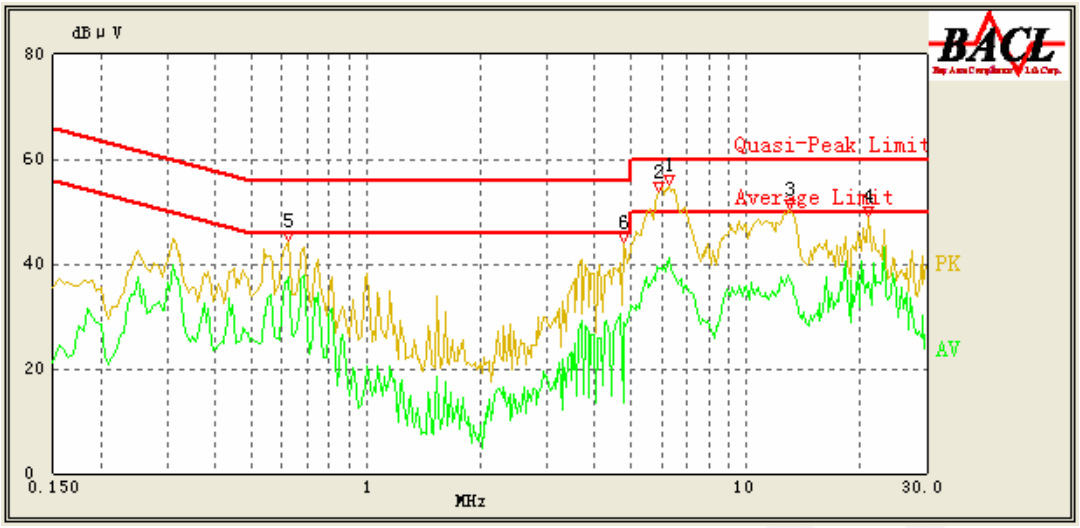
Test Mode: Talking (powered by PoE)

AC 240V/50 Hz, Line



Frequency (MHz)	Corrected Amplitude (dBµV)	Correction Factor (dB)	Limit (dBµV)	Margin (dB)	Detector (PK/Ave./QP)
0.620	37.96	10.23	46.00	8.04	Ave.
5.920	51.45	10.34	60.00	8.55	QP
6.300	39.67	10.35	50.00	10.33	Ave.
5.920	39.64	10.33	50.00	10.36	Ave.
5.615	49.03	10.32	60.00	10.97	QP
13.070	37.73	11.00	50.00	12.27	Ave.
13.070	47.33	11.00	60.00	12.67	QP
6.300	46.58	10.35	60.00	13.42	QP
5.615	35.85	10.32	50.00	14.15	Ave.
9.605	35.83	10.48	50.00	14.17	Ave.
0.620	40.43	10.23	56.00	15.57	QP
9.605	42.85	10.47	60.00	17.15	QP

AC 240V/50 Hz, Neutral:



Frequency (MHz)	Corrected Amplitude (dBµV)	Correction Factor (dB)	Limit (dBµV)	Margin (dB)	Detector (PK/Ave./QP)
0.625	37.54	10.22	46.00	8.46	Ave.
6.300	41.02	10.34	50.00	8.98	Ave.
5.925	50.77	10.33	60.00	9.23	QP
5.925	39.11	10.33	50.00	10.89	Ave.
6.300	48.27	10.34	60.00	11.73	QP
12.995	37.84	10.94	50.00	12.16	Ave.
20.985	36.65	12.46	50.00	13.35	Ave.
12.995	45.65	10.94	60.00	14.35	QP
0.625	40.42	10.22	56.00	15.58	QP
4.770	28.89	10.28	46.00	17.11	Ave.
4.770	33.95	10.28	56.00	22.05	QP
20.985	37.33	12.46	60.00	22.67	QP

Note:
1) Corrected Amplitude = Reading + Correction Factor
2) Correction Factor =LISN/ISN VDF (Voltage Division Factor) + Cable Loss + Pulse Limiter Attenuation
The corrected factor has been input into the transducer of the test software.
3) Margin = Limit – Corrected Amplitude
4) *Within measurement uncertainty!

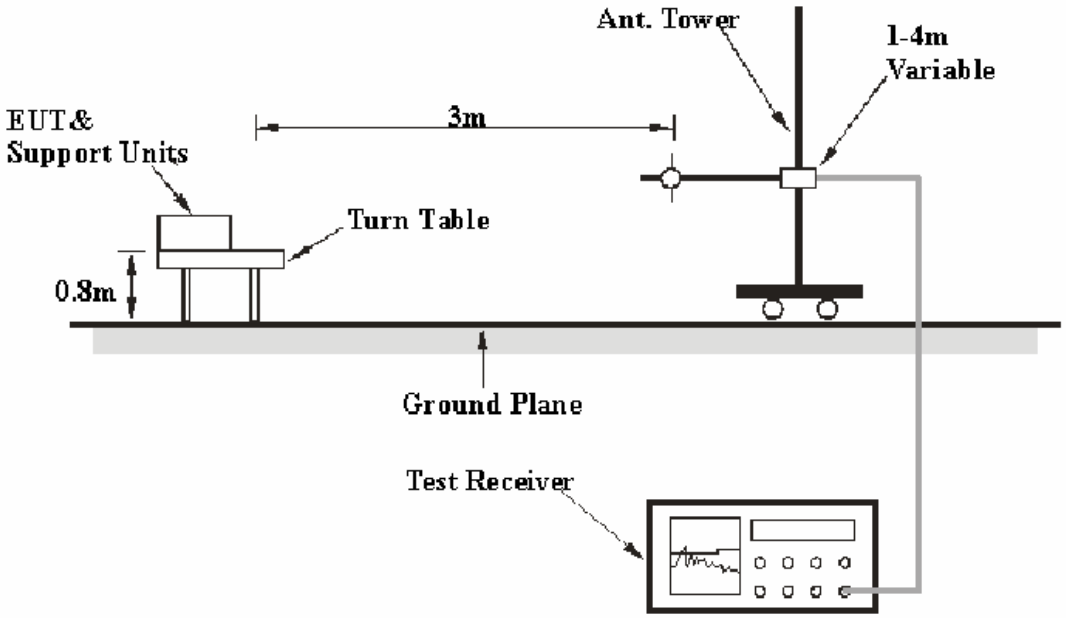
AS/NZS CISPR 22: 2009 §6-RADIATED DISTURBANCE

Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

Based on CISPR 16-4-2, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of a radiation emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is 4.0 dB. (k=2, 95% level of confidence), and the uncertainty will not be taken into consideration for all the test data recorded in the report.

Test System Setup



The radiated emission tests were performed in the 3 meters test site, the setup of EUT is according with CISPR 16-1-4:2010, CISPR16-2-3:2010 measurement procedure, the related limit was specified in the AS/NZS CISPR 22:2009 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 240 VAC/50 Hz power source.

EMI Test Receiver Setup

The system was investigated from 30 MHz to 6 GHz.

During the radiated emission test, the EMI test receiver Setup was set with the following configurations:

Frequency Range	RBW	Video B/W	IF B/W	Detector
30MHz – 1000 MHz	100 kHz	300 kHz	120kHz	QP
Above 1 GHz	1MHz	3 MHz	/	PK
	1MHz	10 Hz	/	Ave.

Test Procedure

For the radiated emissions test, the adapter was connected to AC floor outlet.

Maximizing procedure was performed on the highest emissions to ensure that the EUT complied with all installation combinations.

All data was recorded in the Quasi-peak detection mode for below 1 GHz, and Peak and Average for above 1 GHz.

Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Loss, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

Corrected Amplitude = Meter Reading + Antenna Factor + Cable Loss - Amplifier Gain

The "**Margin**" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7dB means the emission is 7dB below the maximum limit for Class B. The equation for margin calculation is as follows:

Margin = Limit – Corrected Amplitude

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
HP	Amplifier	8447E	1937A01046	2011-11-24	2012-11-23
Rohde & Schwarz	EMI Test Receiver	ESCI	101122	2012-08-08	2013-08-07
Sunol Sciences	Broadband Antenna	JB1	A040904-2	2011-11-28	2012-11-27
Rohde & Schwarz	Signal Analyzer	FSIQ26	8386001028	2011-11-24	2012-11-23
Mini-circuits	Pre-Amplifier	ZVA-213+	N/A	2011-11-24	2012-11-23
Sunol Sciences	Horn Antenna	DRH-118	A052304	2011-12-01	2012-11-30
R&S	Auto test Software	EMC32	V6.30	-	-

*** Statement of Traceability:** Bay Area Compliance Laboratory Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to National Institute of Metrology (NIM)

Test Results Summary

According to the data in the following table, with the worst margin reading is below:

4.09 dB at **3791.8 MHz** in the **Vertical** polarization (Powered by PoE)

Refer to CISPR16-4-2:2011 and CISPR 16-4-1:2009, the measured level is in compliance with the limit if

$$Lm + U(Lm) \leq Llim + Ucispr$$
$$\text{or } U(Lm) \leq Margin + Ucispr$$

The measurement result of EUT is below the limit level by a margin 4.09 dB and
$U_{(Lm)}$(4dB)≤*Margin*(4.09 dB) + U_{cispr}(6.3dB),
so the EUT complies with the limit of the AS/NZS CISPR 22 Class B.

Test Data

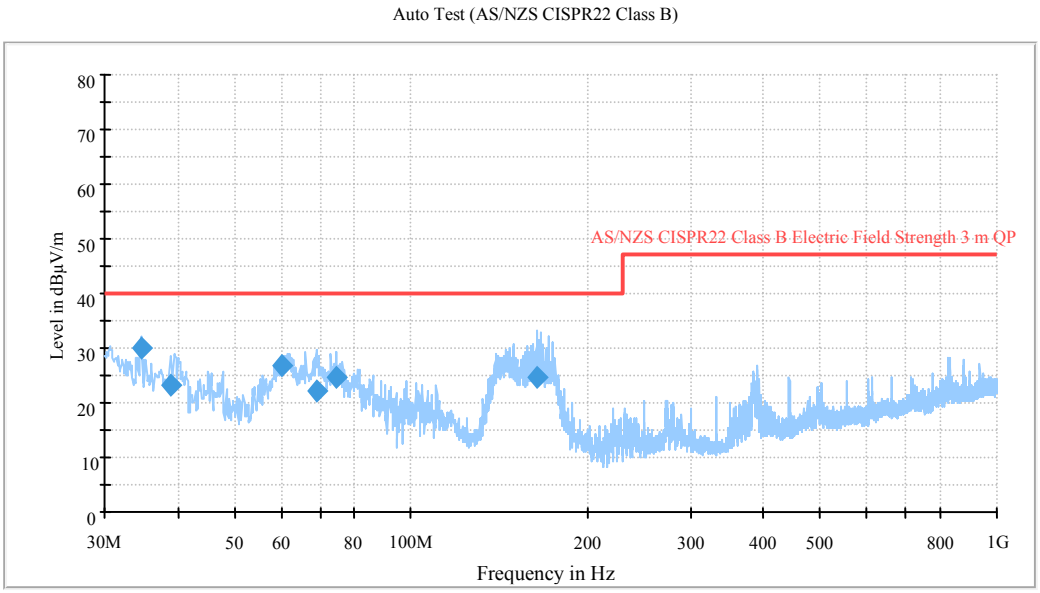
Environmental Conditions

Temperature:	25 ℃
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Andrew Shu on 2012-11-20.

Test Mode: Talking (Powered by adapter)

1) 30MHz ~ 1000 MHz



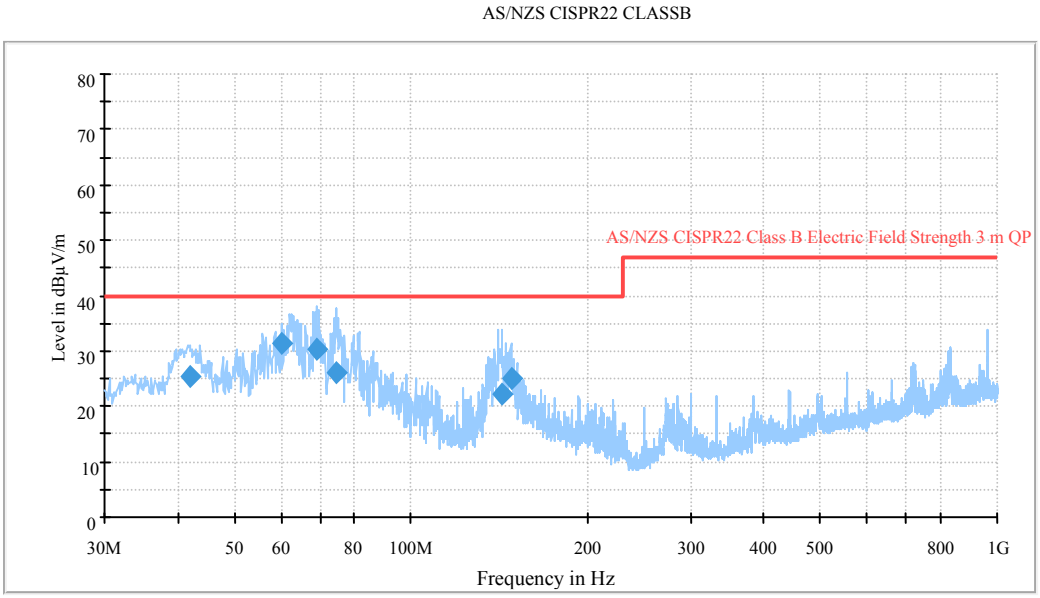
Frequency (MHz)	Corrected Amplitude (dBµV/m)	Antenna Height (cm)	Ant. Polarity (H/V)	Turntable Position (degree)	Correction Factor (dB/m)	Limit (dBµV/m)	Margin (dB)
34.639750	29.8	100.0	V	349.0	-10.4	40.0	10.2
60.228450	26.6	100.0	V	301.0	-20.7	40.0	13.4
164.056750	24.6	111.0	V	272.0	-15.3	40.0	15.4
74.544800	24.5	137.0	V	51.0	-20.2	40.0	15.5
38.956500	23.1	100.0	V	316.0	-13.6	40.0	16.9
69.066650	22.0	187.0	V	200.0	-20.6	40.0	18.0

2) Above 1 GHz

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Corrected Factor (dB)	Corrected Amplitude (dBμV/m	AS/NZS CISPR22 CLASS B	
	Reading (dBμV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBμV/m	Margin (dB)
3790.3	59.71	PK	332	1.2	V	9.70	69.41	74	4.59
3790.4	56.31	PK	62	1.3	H	9.70	66.01	74	7.99
3790.3	36.04	Ave.	332	1.2	V	9.70	45.74	54	8.26
5682.6	51.66	PK	28	1.1	V	12.98	64.64	74	9.36
5681.9	50.44	PK	15	1.2	H	12.98	63.42	74	10.58
3790.4	33.29	Ave.	62	1.3	H	9.70	42.99	54	11.01
5681.9	28.37	Ave.	15	1.2	H	12.98	41.35	54	12.65
5682.6	27.36	Ave.	28	1.1	V	12.98	40.34	54	13.66
1941.8	43.16	PK	91	1.3	H	3.07	46.23	74	27.77
1941.3	42.58	PK	223	1.3	H	3.07	45.65	74	28.35
1941.8	21.26	Ave.	91	1.3	H	3.07	24.33	54	29.67
1941.3	21.06	Ave.	223	1.3	H	3.07	24.13	54	29.87

Test Mode: Talking (Powered by PoE)

1) 30MHz ~ 1000 MHz



Frequency (MHz)	Corrected Amplitude (dBµV/m)	Antenna Height (cm)	Ant. Polarity (H/V)	Turntable Position (degree)	Correction Factor (dB/m)	Limit (dBµV/m)	Margin (dB)
60.234375	31.5	100.0	V	0.0	-20.7	40.0	8.5
68.995250	30.4	112.0	V	0.0	-20.6	40.0	9.6
74.743100	26.2	100.0	V	0.0	-20.2	40.0	13.8
42.132400	25.2	100.0	V	0.0	-15.9	40.0	14.8
148.130050	25.1	112.0	V	150.0	-14.9	40.0	14.9
143.294000	22.2	112.0	V	80.0	-14.5	40.0	17.8

2) Above 1 GHz

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Corrected Factor (dB)	Corrected Amplitude (dBµV/m	AS/NZS CISPR22 CLASS B	
	Reading (dBµV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBµV/m	Margin (dB)
3791.8	60.21	PK	55	1.3	V	9.70	69.91	74	4.09
3790.4	57.22	PK	65	1.2	H	9.70	66.92	74	7.08
3791.8	36.36	Ave.	55	1.2	V	9.70	46.06	54	7.94
5682.7	51.24	PK	96	1.2	V	12.98	64.22	74	9.78
3790.4	34.02	Ave.	65	1.2	H	9.70	43.72	54	10.28
5681.5	50.37	PK	236	1.1	H	12.98	63.35	74	10.65
5681.5	28.63	Ave.	236	1.1	H	12.98	41.61	54	12.39
5682.7	27.36	Ave.	96	1.2	V	12.98	40.34	54	13.66
1941.3	43.69	PK	96	1.2	H	3.07	46.76	74	27.24
1941.1	43.26	PK	25	1.3	V	3.07	46.33	74	27.67
1941.1	22.52	Ave.	25	1.3	V	3.07	25.59	54	28.41
1941.3	21.47	Ave.	96	1.2	H	3.07	24.54	54	29.46

EXHIBIT A - PRODUCT LABELING

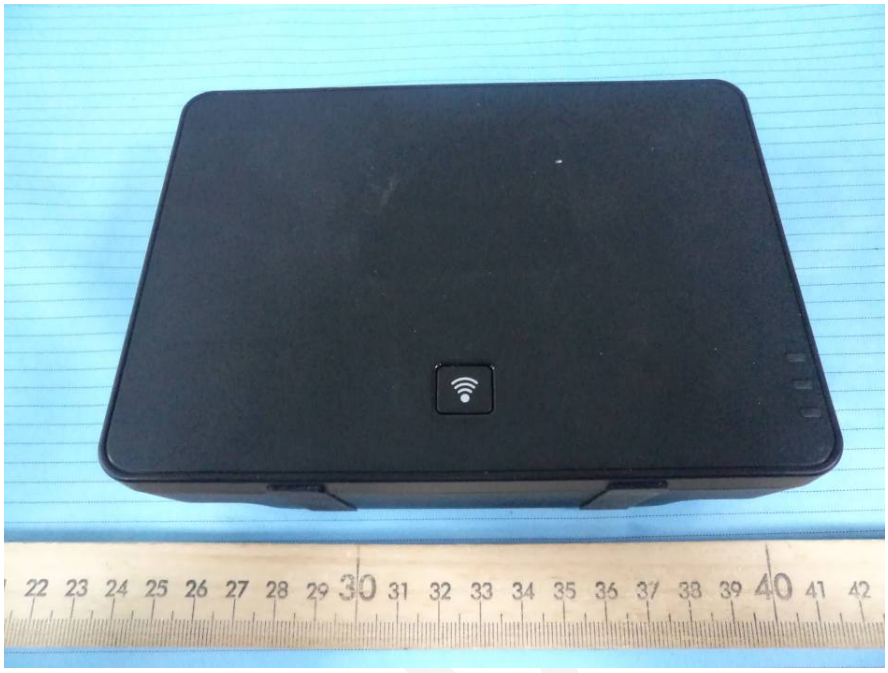
Proposed Label Format

Specifications: Text is Black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing or silk-screened onto the EUT or shall be affixed at a conspicuous location on the EUT.

Proposed Label Location on EUT

EXHIBIT B - EUT PHOTOGRAPHS

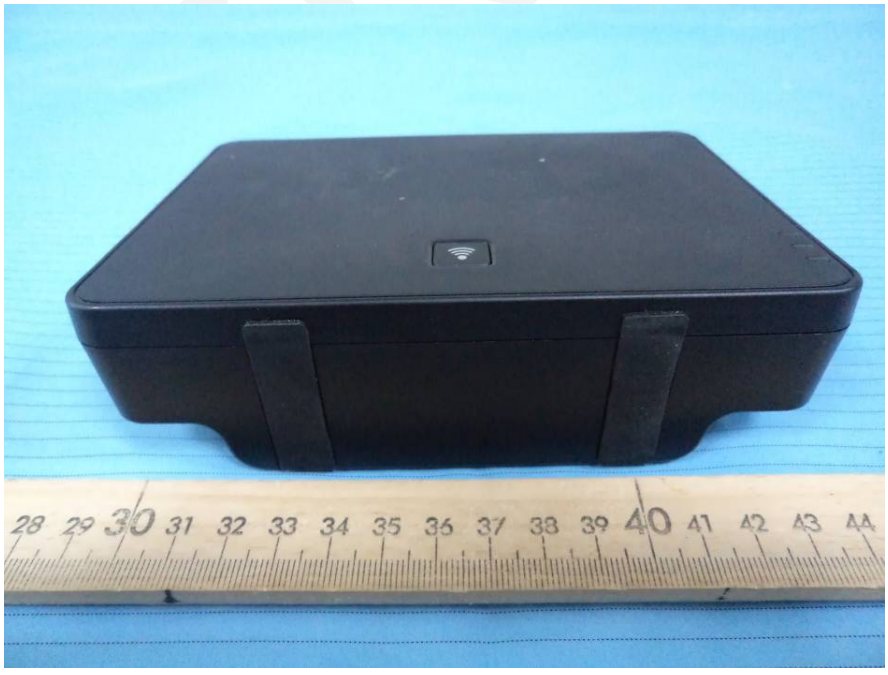
EUT (Base) – Top View



EUT (Base) – Bottom View

EUT (Base) – Front View

EUT (Base) – Rear View

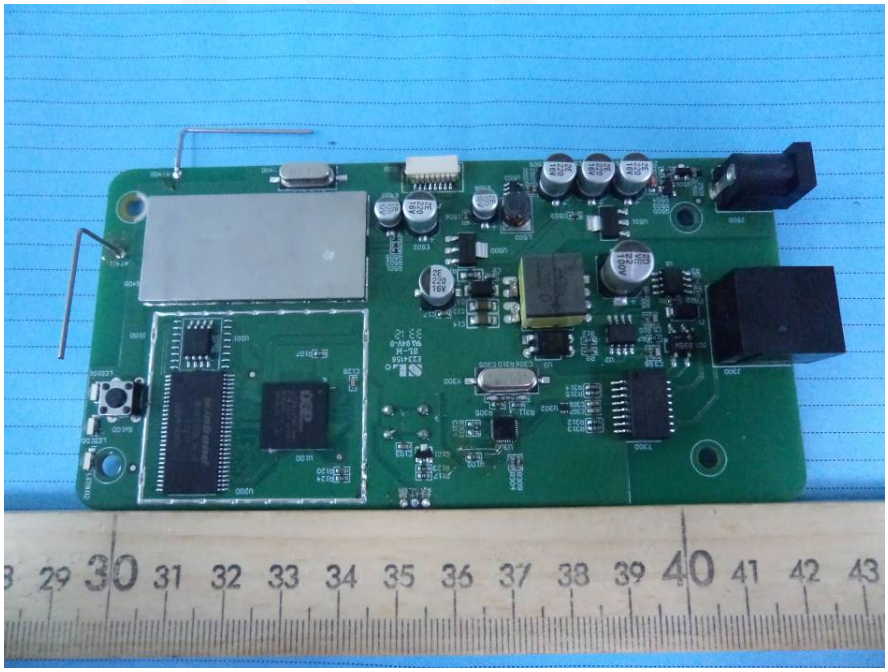


EUT (Base) – Left Side View

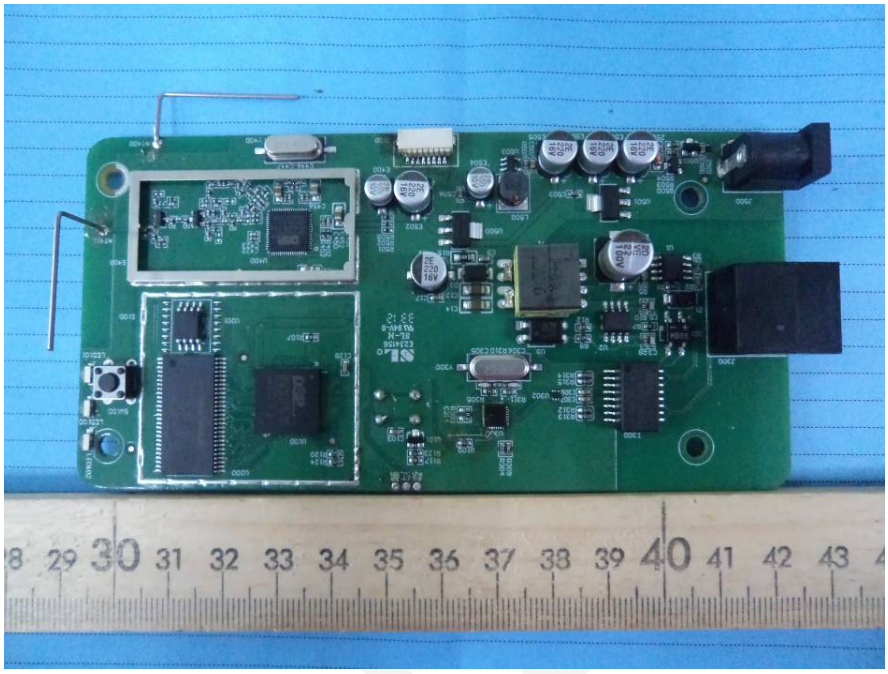
EUT (Base) – Right Side View

EUT (Base) – Cover off View

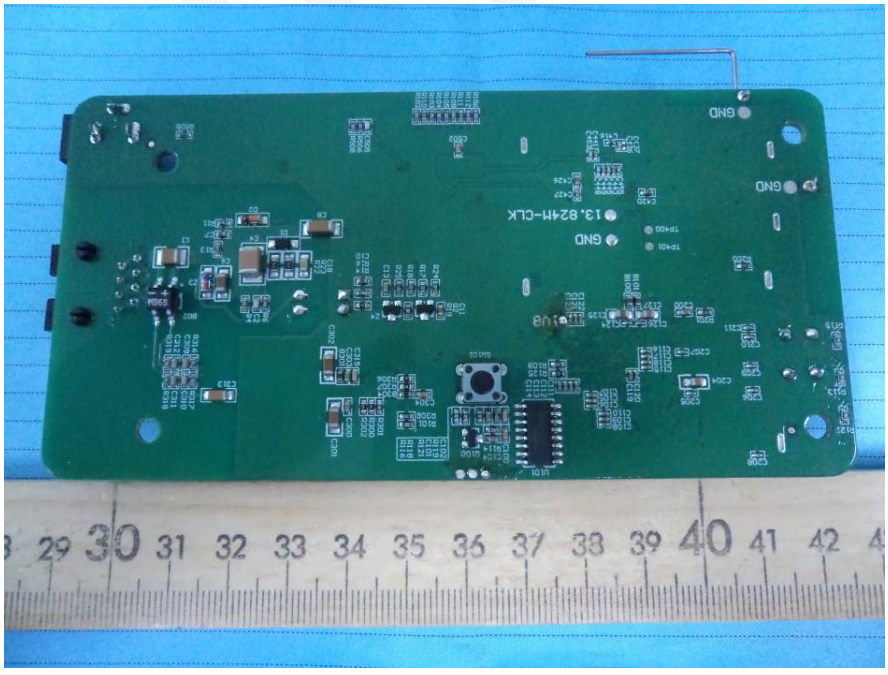
EUT (Base) – Main Board Top View



EUT (Base) – Main Board Shielding off Top View



EUT (Base) – Main Board Bottom View



EUT (Handset) – Front View

EUT (Handset) – Rear View

EUT (Handset) – Top View

EUT (Handset) – Bottom View

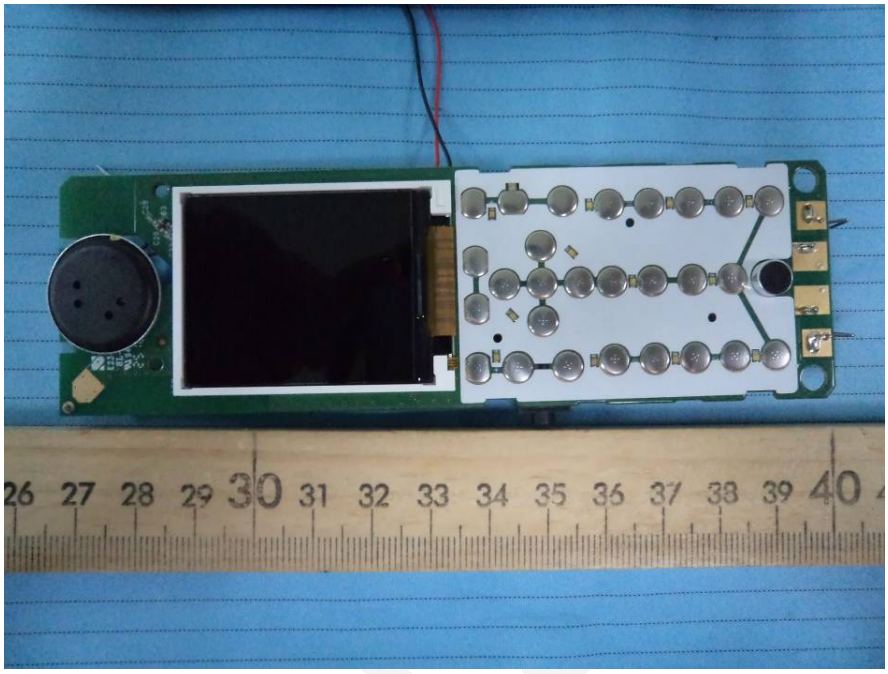
EUT (Handset) – Left Side View

EUT (Handset) – Right Side View

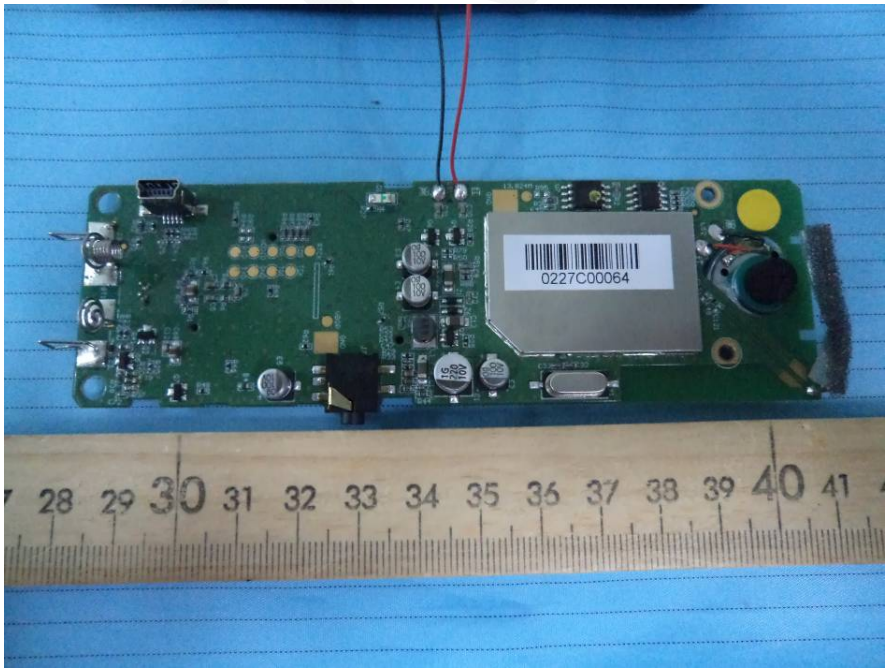
EUT (Handset) – Cover off View 1

EUT (Handset) – Cover off View 2

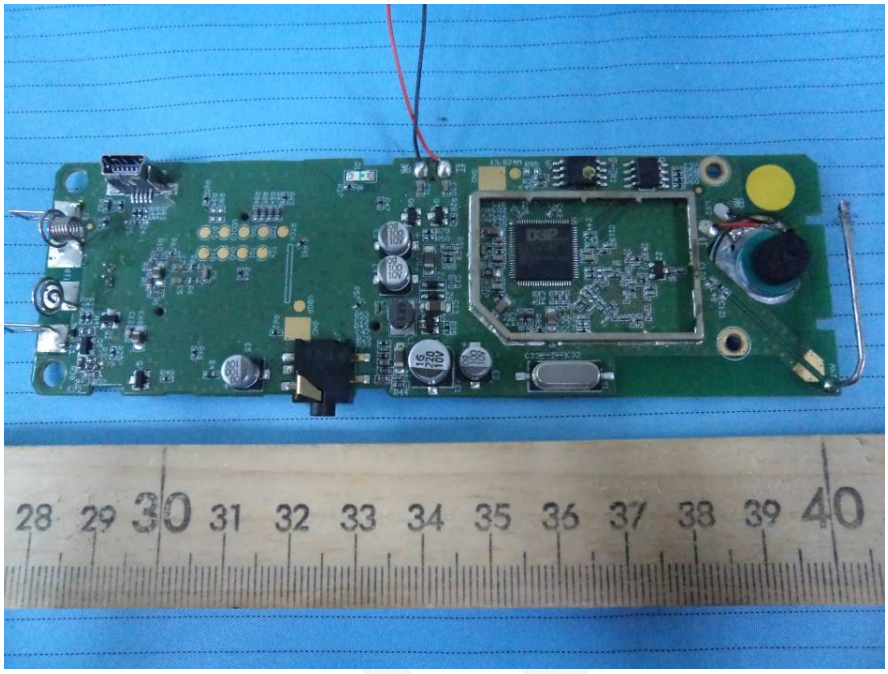
EUT (Handset) – Main Board Top View



EUT (Handset) – Main Board Bottom View



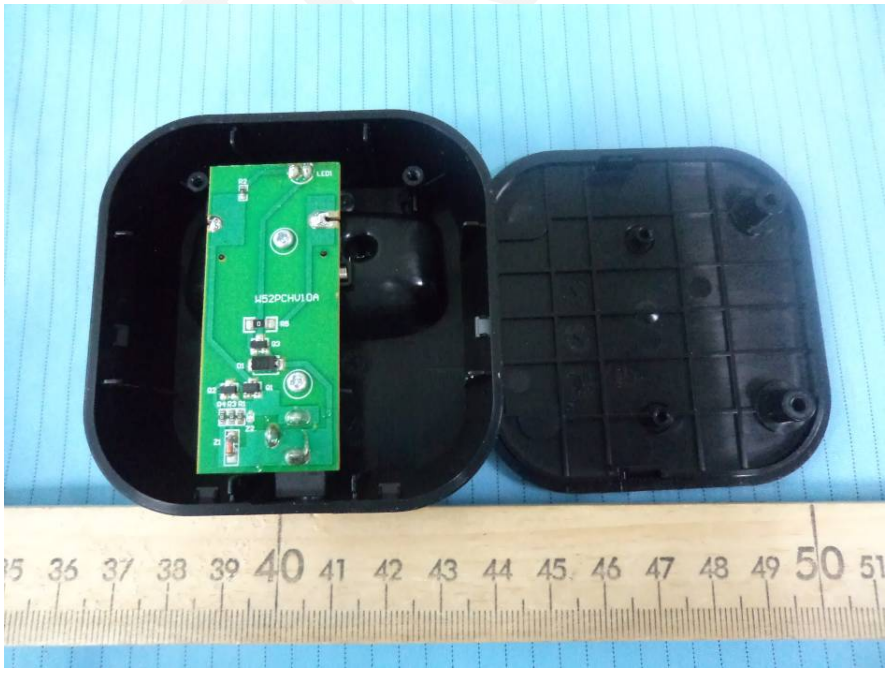
EUT (Handset) – Main Board Shielding off Top View



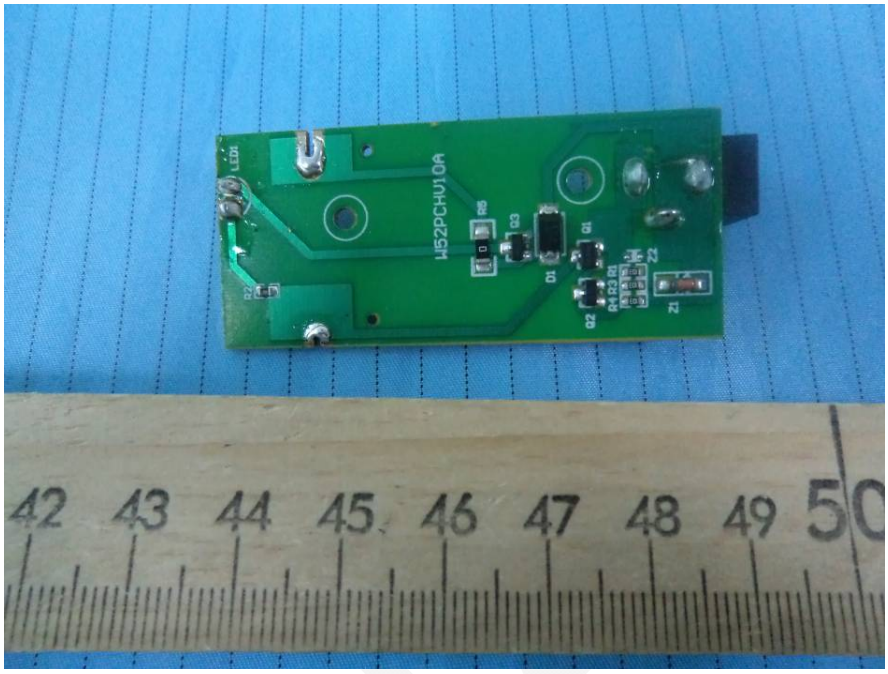
EUT (Charger) – Top View

EUT (Charger) – Bottom View

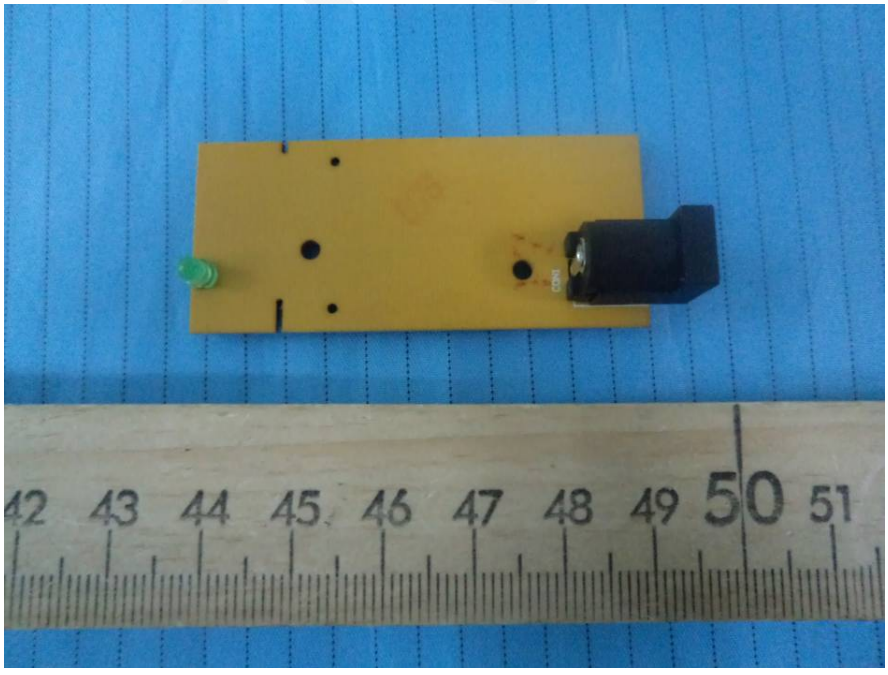
EUT (Charger) – Cover off View



EUT (Charger) – Main Board Top View



EUT (Charger) – Main Board Bottom View



EUT – Adapter View

EUT – Adapter Label View

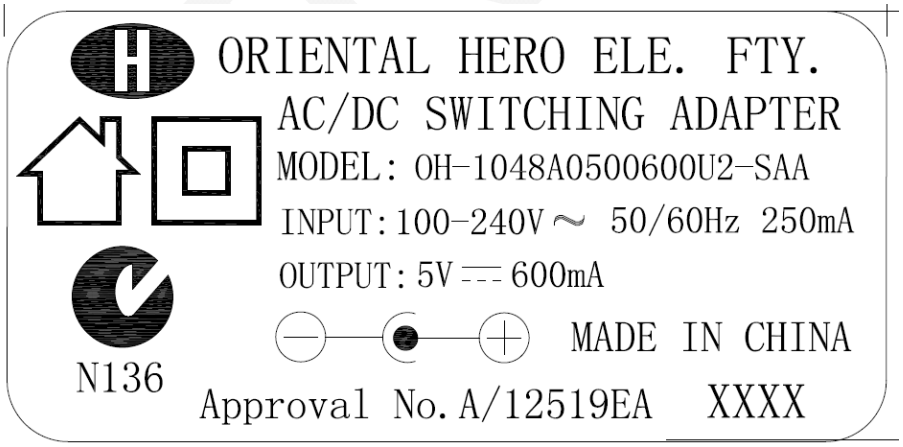


EXHIBIT C - TEST SETUP PHOTOGRAPHS

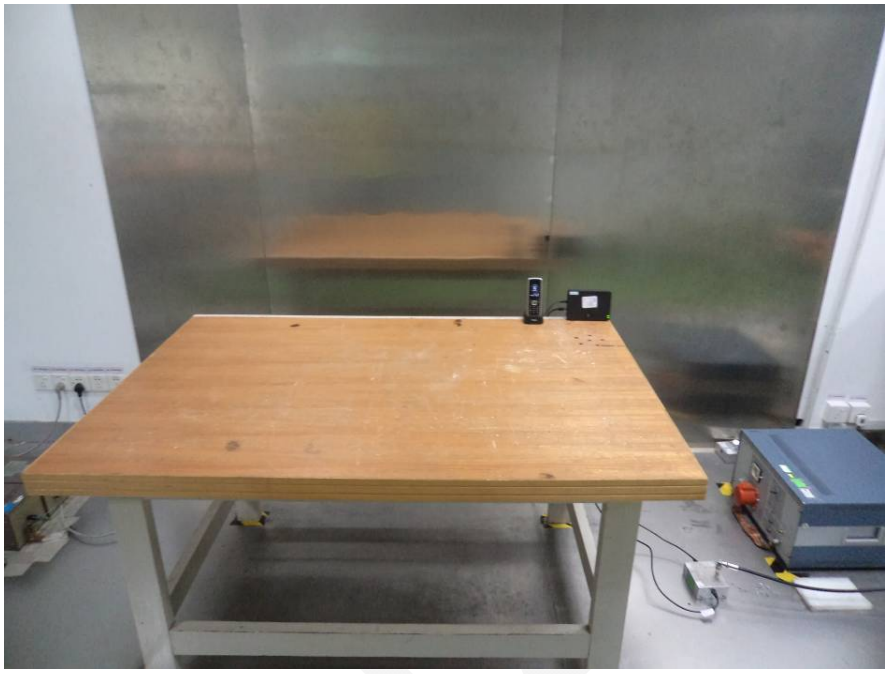
Conducted Disturbance - Front View (base-powered by adapter)

Conducted Disturbance - Side View (base-powered by adapter)

Conducted Disturbance - Front View (handset-powered by adapter)

Conducted Disturbance - Side View (handset-powered by adapter)

Conducted Disturbance - Front View (RJ 45 Port)



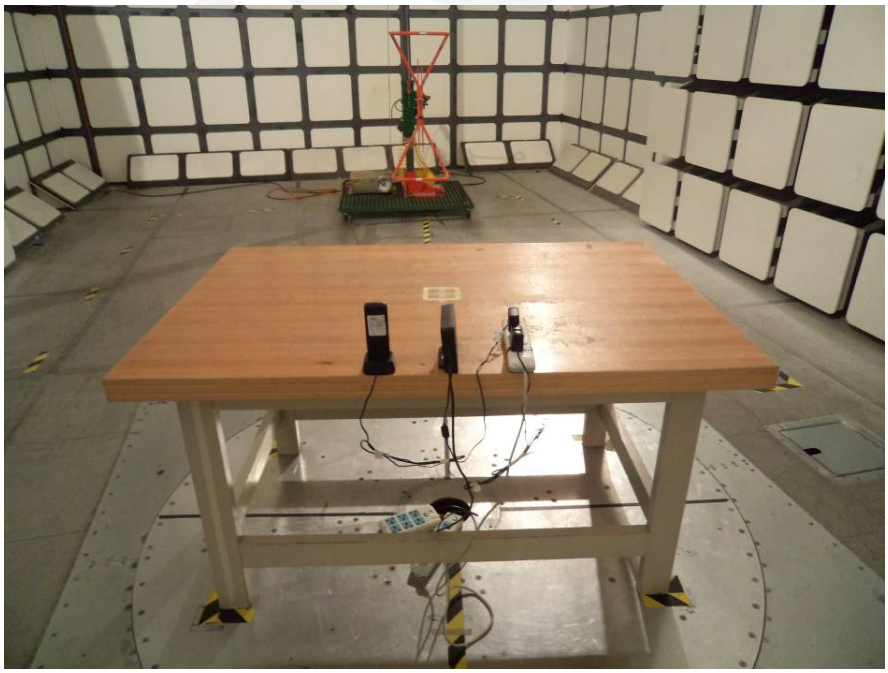
Conducted Disturbance - Side View (RJ 45 Port)

Conducted Disturbance - Front View (powered by PoE)

Conducted Disturbance - Side View (powered by PoE)

Radiated Disturbance - Front View (30 MHz-1 GHz, powered by adapter)

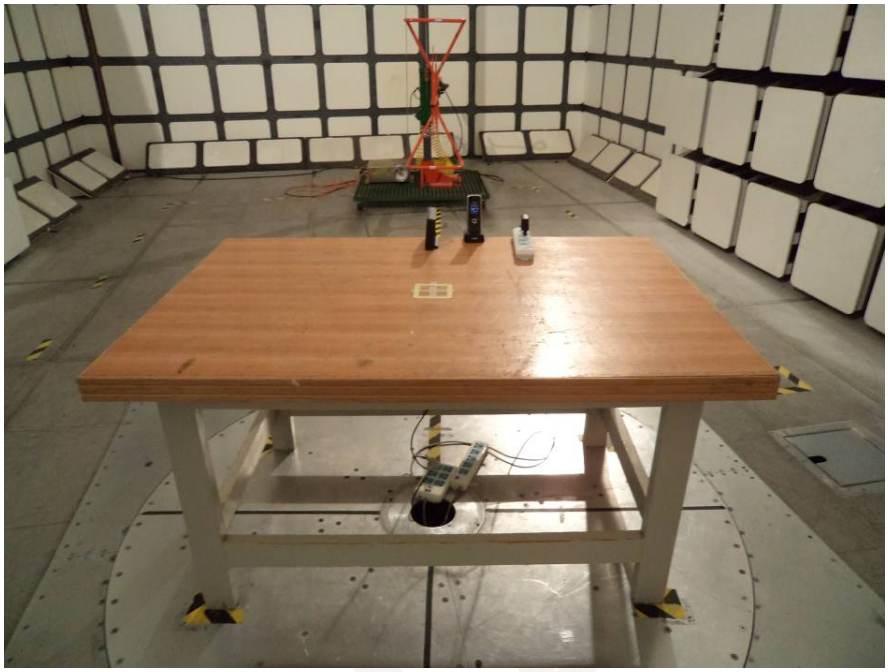
Radiated Disturbance - Rear View (30 MHz-1 GHz, powered by adapter)



Radiated Disturbance - Front View (Above 1 GHz, powered by adapter)

Radiated Disturbance - Rear View (Above 1 GHz, powered by adapter)

Radiated Disturbance - Front View (30 MHz-1 GHz, powered by PoE)



Radiated Disturbance - Rear View (30 MHz-1 GHz, powered by PoE)

Radiated Disturbance - Front View (Above 1 GHz, powered by PoE)

Radiated Disturbance - Rear View (Above 1 GHz, powered by PoE)

DECLARATION LETTER

Yealink (Xiamen) Network Technology Co., LTD.
4th-5th Floor, South Building, No.63 Wanghai Road,2nd Software Park, Xiamen, China.
Tel: 86-592-5702000-2801 Fax: 86-592-5702455

2012-11-20

Product Similarity Declaration Letter

To Whom It May Concern,

We, Yealink （Xiamen）Network Technology Co.,Ltd. hereby declare that our product IP DECT Phone, the model W52P, W52H, W52Duo are electrically identical, they have the same PCB layout and schematic, the only difference is W52P has one base and one handset, W52H has only one handset, and W52Duo has one base and two handsets. Model W52P was tested by BACL.

Please contact me if you have any question.

Signature:

Stone Lu：
Vice General Manager

******* END OF REPORT *******